

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,830	HAHN ET AL.	
Examiner	Art Unit	
Niki M. Eloshway	3727	

SEARCHED							
Class	Subclass	Date	Examiner				
215	305, 295, 329, 334, dig. 2,	9/13/2005	NME				
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